

Appl. No. 10/718,859
Amdt. dated April 15, 2005
Reply to Office action of December 2, 2004

The listing of claims will replace all prior versions, and listings, of claims in this application:

Listing of Claims:

1. (cancelled)

2. (currently amended) [The method of claim 1] Method enabling a command to switch the measure mode to be entered in a dimension-measuring column provided with a probe tip,

wherein said command to switch the measure mode is entered by only making use of the position of said probe tip,

wherein said command to switch the measure mode is entered by pressing the probe tip against a piece to be measured during a time interval greater than a predetermined value.

3. (original) The method of claim 2, wherein a measurement of the probing point is effected when the probe tip is pressed against said piece to be measured during a time interval shorter than said predetermined value.

Claims 4-11 (canceled)

12. (cancelled)

13. (currently amended) [The method of claim 12] Method enabling a command to switch the measure mode to be entered in a dimension-measuring column provided with a probe tip,

wherein said command to switch the measure mode is entered by only making use of the position of said probe tip,

wherein an aural and/or visual signal is emitted during a said mode switch,

wherein said command to switch the measure mode is entered by pressing the probe tip against a piece to be measured during a time interval greater than a predetermined value.

Claims 14-16 (canceled)

17. (cancelled)

18. (currently amended) [The measuring column of claim 17]
Dimension-measuring column, comprising:

a probe tip designed for being brought into contact with the piece to be measured,

a displacement mechanism of said probe tip,

a measuring and displaying system that allows the position of said probe tip to be determined and displayed, said measuring and displaying system being able to function according to several distinct modes,

wherein at least one of said measure modes can be selected by acting on the position of the probe tip, without any other handling operating being necessary,

wherein said measure mode can be selected by pressing the probe tip against the piece to be measured during a time interval greater than a predetermined value.

19. (original) The measuring column of claim 18, wherein the measurement of the probing point is effected when the probe tip is pressed against said piece to be measured during a time interval shorter than said predetermined value.

Claims 20-27 (canceled)

28. (cancelled)

29. (original) Computer data carrier comprising a command program for measuring and displaying system in a dimension-measuring column, said program enabling the position of the probe tip of said measuring column to be determined and displayed, said program being capable of making said measuring and displaying system function according to several distinct modes,

wherein said program enables another of said measure modes to be selected by acting on the position of the probe tip.

30. (cancelled)

31. (cancelled)

32. (cancelled)

33. (currently amended) [The method of claim 30] Method enabling a command to switch a measure mode to be entered in a dimensional-measuring column provided with a probe tip,

wherein said command to switch the measure mode is entered by means of deliberate handling operations of a height-command crank,

wherein said command to switch the measure mode is entered by pressing said probe tip against a piece to be measured during a time interval shorter than a predetermined value.

34. (cancelled)

35. (cancelled)

36. (previously presented) Method enabling a command to switch the measure mode to be entered in a dimension-measuring column provided with a probe tip,

wherein said dimension-measuring column enables detecting a pressing force between the probe tip and a piece to be measured;

wherein said command to switch the measure mode is entered by maintaining the probe tip pressed against said piece to be measured during a time interval longer than a predetermined time greater than zero.

37. (previously presented) Dimension-measuring column, comprising:
a probe tip designed for being brought into contact with the piece to be measured,

a height-command crank for displacing said probe tip,

a measuring and displaying system that allows the position of said probe tip to be determined and displayed,

wherein a command to switch the measure mode is entered upon detection of a pressing force between the probe tip and a piece to be measured during a time interval longer than a predetermined time greater than zero.

38. (previously presented) Method enabling a command to switch the measure mode to be entered in a height-measuring column provided with a probe tip,

said height-measuring column having a plurality of measure modes for measuring a plurality of different parameters of a piece,

wherein said command to switch the measure mode is entered by pressing said probe tip against a piece to be measured,

wherein said height-measuring column remains in said measure mode as long as a sufficient pressing force is exerted by the probe tip against the piece to be measured.

39. (previously presented) Method enabling a command to switch the measure mode to be entered in a dimension-measuring column provided with a probe tip and with one or more measuring axis, wherein said command to switch the measure mode is entered by only making use of the position of said probe tip along only one of said one or more measuring axis.

40. (cancelled)

41. (previously presented) The method of claim 36, wherein the measurement mode is limited to only a single dimension.

42. (previously presented) The column of claim 37, wherein the measuring and displaying system is only operable in a single dimension.

43. (previously presented) The method of claim 3, wherein said predetermined value is a required duration that is greater than the time interval needed to obtain the measurement.

44. (previously presented) The method of claim 19, wherein said predetermined value is a required duration that is greater than the time interval needed to obtain the measurement.

45. (previously presented) The method of claim 33, wherein said predetermined value is a required duration that is greater than the time interval needed to obtain the measurement.